74AC11652 OCTAL BUS TRANSCEIVER AND REGISTERS WITH 3-STATE OUTPUTS

SCAS088A - DECEMBER 1989 - REVISED APRIL 1996

- Independent Registers and Enables for A and B Buses
- Multiplexed Real-Time and Stored Data
- Inverting Data Paths
- Flow-Through Architecture Optimizes PCB Layout
- Center-Pin V_{CC} and GND Configurations Minimize High-Speed Switching Noise
- EPIC[™] (Enhanced-Performance Implanted CMOS) 1-µm Process
- 500-mA Typical Latch-Up Immunity at 125°C

description

The 74AC11652 consists of bus transceiver circuits, D-type flip-flops, and control circuitry arranged for multiplexed transmission of data directly from the data bus or from the internal

DW PACKAGE (TOP VIEW) **OEAB** 28 CLKAB 27 🛮 SAB Α1 2 Α2 3 26 B1 A3 25 ¶ B2 4 A4 24 ∏ B3 23 N B4 GND 6 GND 22 V_{CC} 21 V_{CC} GND GND 9 20 B5 A5 10 19 **∏** B6 18 B7 A6 11 П ва A7 12 17 **A8** 13 16 CLKBA **OEBA** 15 **∏** SBA 14

storage registers. Output-enable (OEAB and \overline{OEBA}) inputs are provided to control the transceiver functions. The select-control (SAB and SBA) inputs are provided to select whether real-time or stored data is transferred. A low input level selects real-time data, and a high input level selects stored data. Figure 1 illustrates the four fundamental bus-management functions that can be performed with the 74AC11652.

Data on the A or B bus, or both, can be stored in the internal D flip-flops by low-to-high transitions at the appropriate clock (CLKAB or CLKBA) inputs, regardless of the select- or enable-control pins. When SAB and SBA are in the real-time transfer mode, it is also possible to store data without using the internal D-type flip-flops by simultaneously enabling OEAB and OEBA. In this configuration, each output reinforces its input. Thus, when all other data sources to the two sets of bus lines are at high impedance, each set remains at its last state.

The 74AC11652 is characterized for operation from -40° C to 85° C.



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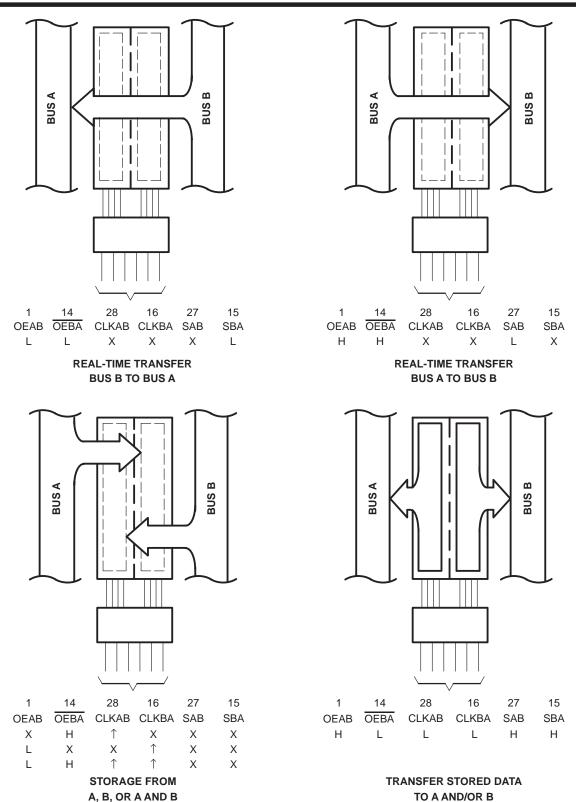


Figure 1. Bus-Management Functions



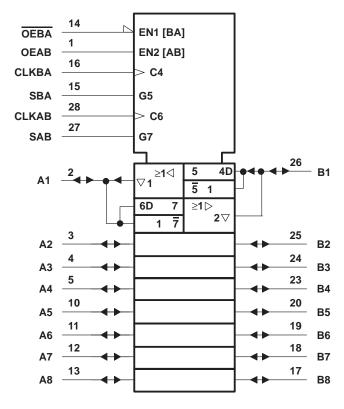
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FUNCTION TABLE

		INPU	гѕ			DATA	1/0†	OPERATION OR FUNCTION		
OEAB	OEBA	CLKAB	CLKBA	SAB	SBA	A1 THRU A8	B1 THRU B8	OPERATION OR FUNCTION		
L	Н	L	L	Х	Х	Input	Input	Isolation		
L	Н	\uparrow	\uparrow	X	X	Input	Input	Store A and B data		
X	Н	\uparrow	L	X	X	Input	Unspecified [‡]	Store A, hold B		
Н	Н	\uparrow	\uparrow	X‡	X	Input	Output	Store A in both registers		
L	X	L	\uparrow	X	X	Unspecified [‡]	Input	Hold A, store B		
L	L	\uparrow	\uparrow	X	χ‡	Output	Input	Store B in both registers		
L	L	Χ	Χ	X	L	Output	Input	Real-time B data to A bus		
L	L	Χ	L	X	Н	Output	Input	Stored B data to A bus		
Н	Н	Χ	Χ	L	X	Input	Output	Real-time A data to B bus		
Н	Н	L	Χ	Н	X	Input	Output	Stored A data to B bus		
н	L	L	L	Н	Н	Output	Output	Stored A data to B bus and stored B data to A bus		

[†] The data output functions may be enabled or disabled by a variety of level combinations at the OEAB or OEBA inputs. Data input functions are always enabled; i.e., data at the bus pins is stored on every low-to-high transition on the clock inputs.

logic symbol§



§ This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

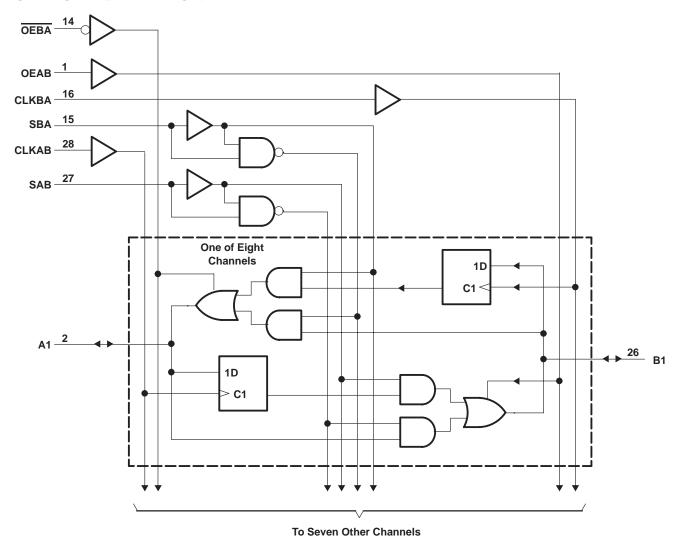


[‡] Select control = L; clocks can occur simultaneously.

Select control = H; clocks must be staggered to load both registers.

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logic diagram (positive logic)



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)

Supply voltage range, V _{CC}	
Input voltage range, V _I (see Note 1)	$-0.5 \text{ V to V}_{CC} + 0.5 \text{ V}$
Output voltage range, VO (see Note 1)	$-0.5 \text{ V to V}_{CC} + 0.5 \text{ V}$
Input clamp current, I_{IK} ($V_I < 0$ or $V_I > V_{CC}$)	±20 mA
Output clamp current, I_{OK} ($V_O < 0$ or $V_O > V_{CC}$)	±50 mA
Continuous output current, I_O ($V_O = 0$ to V_{CC})	±50 mA
Continuous current through V _{CC} or GND	±200 mA
Maximum power dissipation at $T_A = 55^{\circ}C$ (in still air) (see Note 2)	1.7 W
Storage temperature range, T _{stg}	−65°C to 150°C

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

^{2.} The maximum package power dissipation is calculated using a junction temperature of 150°C and a board trace length of 750 mils.



NOTES: 1. The input and output voltage ratings may be exceeded if the input and output clamp-current ratings are observed.

recommended operating conditions

			MIN	NOM	MAX	UNIT	
Vcc	Supply voltage		3	5	5.5	V	
		V _{CC} = 3 V	2.1				
٧ _{IH}	High-level input voltage	V _{CC} = 4.5 V	3.15			V	
		V _{CC} = 5.5 V	3.85				
		V _{CC} = 3 V			0.9		
\vee_{IL}	Low-level input voltage V _{CC} = 4.5 V				1.35	V	
		V _{CC} = 5.5 V			1.65		
VI	Input voltage		0		VCC	V	
VO	Output voltage		0		VCC	V	
		V _{CC} = 3 V			-4		
lон	High-level output current	V _{CC} = 4.5 V			-24	mA	
		V _{CC} = 5.5 V			-24		
		V _{CC} = 3 V			12		
l _{OL}	Low-level output current	V _{CC} = 4.5 V			24	mA	
		V _{CC} = 5.5 V			24		
Δt/Δν	Input transition rice or fall rate	Control pins	0		5	ns/V	
Δι/Δν	Input transition rise or fall rate	Data	0		10		
TA	Operating free-air temperature	-	-40		85	°C	

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

DA	DAMETER	TEST COMPLICATE	V	T,	_Δ = 25°C	;	MAIN	AA A V	LINUT
PA	RAMETER	TEST CONDITIONS	VCC	MIN	TYP	MAX	MIN	MAX	UNIT
			3 V	2.9			2.9		
		I _{OH} = – 50 μA	4.5 V	4.4			4.4		
			5.5 V	5.4			5.4		
VOH	$I_{OH} = -4 \text{ mA}$	3 V	2.58			2.48		V	
			4.5 V	3.94			3.8		
		I _{OH} = – 24 mA	5.5 V	4.94			4.8		
		I _{OH} = -75 mA [†]	5.5 V				3.85		
			3 V			0.1		0.1	
		I _{OL} = 50 μA	4.5 V			0.1		0.1	
			5.5 V			0.1		0.1	
V_{OL}		$I_{OL} = 12 \text{ mA}$	3 V			0.36		0.44	V
		I _{OL} = 24 mA	4.5 V			0.36		0.44	
		10L - 24 IIIA	5.5 V			0.36		0.44	
		$I_{OL} = 75 \text{ mA}^{\dagger}$	5.5 V					1.65	
lį	Control inputs	$V_I = V_{CC}$ or GND	5.5 V			±0.1		±1	μΑ
loz‡	A or B ports	$V_O = V_{CC}$ or GND	5.5 V			±0.5		±5	μΑ
ICC		$V_I = V_{CC}$ or GND, $I_O = 0$	5.5 V			8		80	μΑ
Ci	Control inputs	$V_I = V_{CC}$ or GND	5 V		4.5				pF
Cio	A or B ports	VO = VCC or GND	5 V		12				pF

[†] Not more than one output should be tested at a time, and the duration of the test should not exceed 10 ms.

[‡] For I/O ports, the parameter IOZ includes the input leakage current.



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timing requirements over recommended operating free-air temperature range, V_{CC} = 3.3 V \pm 0.3 V (unless otherwise noted) (see Figure 2)

		T _A = 25°C		MIN	MAX	UNIT
		MIN	MAX	IVIIIV	IVIAA	ONII
fclock	Clock frequency	0	65	0	65	MHz
t _W	Pulse duration, CLK high or low	7.7		7.7		ns
t _{su}	Setup time, A or B before CLKAB↑ or CLKBA↑	6		6		ns
th	Hold time, A or B after CLKAB↑ or CLKBA↑	1	·	1		ns

timing requirements over recommended operating free-air temperature range, V_{CC} = 5 V \pm 0.5 V (unless otherwise noted) (see Figure 2)

		T _A = 2	T _A = 25°C		MAX	UNIT
		MIN	MAX	MIN	WAA	CIVIT
fclock	Clock frequency	0	105	0	105	MHz
t _W	Pulse duration, CLK high or low	4.8		4.8		ns
t _{su}	Setup time, A or B before CLKAB↑ or CLKBA↑	4.5		4.5		ns
th	Hold time, A or B after CLKAB↑ or CLKBA↑	1		1		ns

switching characteristics over recommended operating free-air temperature range, V_{CC} = 3.3 V \pm 0.3 V (unless otherwise noted) (see Figure 2)

PARAMETER	FROM	то	T,	λ = 25°C	;	MIN	MAX	UNIT
PARAMETER	(INPUT)	(OUTPUT)	MIN	TYP	MAX	IVIIIVI	WAX	UNIT
f _{max}			65			65		MHz
^t PLH	A or B	B or A	2.9	8.5	11.1	2.9	12.9	ns
^t PHL		DUIA	3.9	10.3	12.9	3.9	14.2	115
^t PLH	CLKBA or CLKAB	A or B	4.3	11.2	14.3	4.3	16.2	nc
^t PHL	CLNDA OI CLNAD	AOID	5.3	13.1	16.2	5.3	17.8 ns	115
^t PLH	SBA or SAB [†]	A or B	3.4	9.4	12	3.4	13.7	ns
^t PHL	(A or B high)	AUID	4.7	11.5	14.3	4.7	15.6	
^t PLH	SBA or SAB†	A or B	3.9	10.5	13.3	3.9	14.9	ns
^t PHL	(A or B low)	AUID	4.8	12.1	16.3	4.8	17.7	115
^t PZH	OEBA	A	4.3	11.1	14.5	4.3	16.5	ns
^t PZL	OEBA	A	5.2	14.4	19.8	5.2	22	115
^t PHZ	OFDA	А	3.7	6.4	8.1	3.7	8.5	ns
t _{PLZ}	OEBA	A	3.5	6	7.8	3.5	8.2	115
^t PZH	OEAB	В	4.7	11.6	15	4.7	16.9	no
^t PZL	OEAB	D	5.6	14.8	19.9	5.6	21.9	ns
^t PHZ	OEAB	В	4	6.6	8.2	4	8.6	
tpLZ	OLAB	٥	3.5	6.1	7.7	3.5	8	ns

[†] These parameters are measured with the internal output state of the storage register opposite that of the bus input.



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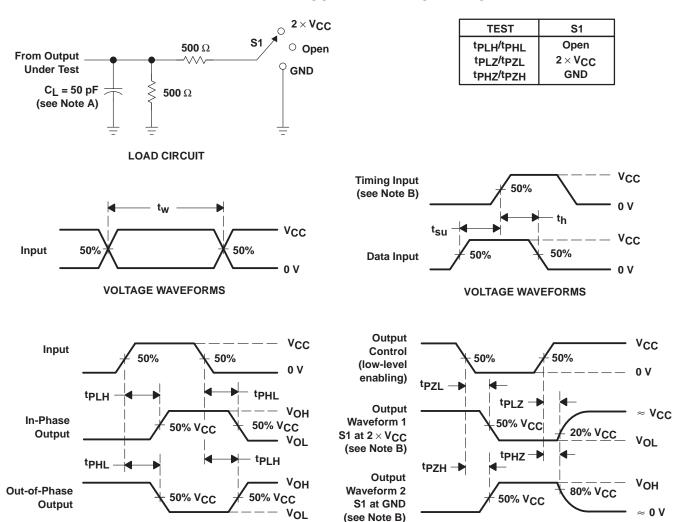
switching characteristics over recommended operating free-air temperature range, V_{CC} = 5 V \pm 0.5 V (unless otherwise noted) (see Figure 2)

PARAMETER	FROM	то	T,	չ = 25°C	;	MIN	MAX	UNIT
FARAWETER	(INPUT)	(OUTPUT)	MIN	TYP	MAX	IVIIIV	IVIAA	ONIT
f _{max}			105			105		MHz
^t PLH	A or B	B or A	2.4	5.2	7.6	2.4	8.6	ns
t _{PHL}		BULA	3.1	6	8.7	3.1	9.6	115
t _{PLH}	CLKBA or CLKAB	A or B	3.6	6.7	9.5	3.6	10.7	ns
^t PHL		AUID	4.4	7.8	10.8	4.4	12	115
t _{PLH}	SBA or SAB (A or B high)	A or B	2.9	5.6	8.1	2.9	9.1	ns
t _{PHL}		AUID	3.8	6.9	9.6	3.8	10.7	115
t _{PLH}	SBA or SAB	SBA or SAB A or B	3.3	6.2	8.8	3.3	9.9	ns
t _{PHL}	(A or B low)	AUID	4	7.1	9.9	4	10.9	115
^t PZH	OFDA	А	3.3	6.6	9.6	3.3	10.9	ns
tPZL	OEBA	A	4.2	7.4	10.9	4.2	12.2	115
^t PHZ	OFDA	A	3.6	5.5	7.2	3.6	7.6	ns
tPLZ	OEBA	A	3.3	5	6.7	3.3	7.1	115
^t PZH	OEAR	В	4.1	7.2	10.1	4.1	11.3	no
tPZL	OEAB	В	4.6	7.9	11.1	4.6	12.3	ns
t _{PHZ}	OEAB	D	3.9	5.6	7.3	3.9	7.6	nc
t _{PLZ}	VEAD	В	3.4	5.2	6.8	3.4	7.2	ns

operating characteristics, $V_{CC} = 5 \text{ V}$, $T_A = 25^{\circ}\text{C}$

PARAMETER			TEST CON	TYP	UNIT	
C _{pd}	Dower dissination conscitones nor transceiver	Outputs enabled	C 50 pF	f = 1 MHz	60	pF
	Power dissipation capacitance per transceiver	Outputs disabled	$C_L = 50 \text{ pF},$	I = I IVIDZ	14	pr

PARAMETER MEASUREMENT INFORMATION



NOTES: A. C_I includes probe and jig capacitance.

VOLTAGE WAVEFORMS

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR \leq 10 MHz, $Z_0 = 50 \Omega$, $t_f = 3 \text{ ns}$, $t_f = 3 \text{ ns}$.

VOLTAGE WAVEFORMS

D. The outputs are measured one at a time with one input transition per measurement.

Figure 2. Load Circuit and Voltage Waveforms



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